

Is Now Part of



ON Semiconductor®

To learn more about ON Semiconductor, please visit our website at www.onsemi.com

Please note: As part of the Fairchild Semiconductor integration, some of the Fairchild orderable part numbers will need to change in order to meet ON Semiconductor's system requirements. Since the ON Semiconductor product management systems do not have the ability to manage part nomenclature that utilizes an underscore (_), the underscore (_) in the Fairchild part numbers will be changed to a dash (-). This document may contain device numbers with an underscore (_). Please check the ON Semiconductor website to verify the updated device numbers. The most current and up-to-date ordering information can be found at www.onsemi.com. Please email any questions regarding the system integration to Fairchild <a href="general-regarding-numbers-n

ON Semiconductor and the ON Semiconductor logo are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any EDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officer



June 2016

FCH023N65S3

N-Channel SuperFET[®] III MOSFET 650 V, 75 A, 23 m Ω

Features

- 700 V @ T_J = 150°C
- Typ. $R_{DS(on)} = 19.5 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. Q_g = 222 nC)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 1980 pF)
- · 100% Avalanche Tested
- · RoHS Compliant

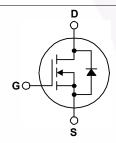
Applications

- Telecom / Server Power Supplies UPS / Solar
- · Industrial Power Supply

Description

SuperFET[®] III MOSFET is Fairchild Semiconductor's brandnew high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate. Consequently, SuperFET III MOSFET is suitable for various DC/AC power conversion for system miniaturization and higher efficiency.





Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol		Parameter		FCH023N65S3_F155	Unit
V _{DSS}	Drain to Source Voltage			650	V
V	Cata to Course Voltage	- DC		±30	V
V_{GSS}	Gate to Source Voltage	- AC	(f > 1 Hz)	±30	V
	Drain Current	- Continuous (T _C = 25°C)		75	Α
ID	Drain Current	- Continuous (T _C = 100°C)		65.8	A
I _{DM}	Drain Current	- Pulsed	(Note 1)	300	Α
E _{AS}	Single Pulsed Avalanche Energy (Note 2)			2025	mJ
I _{AR}	Avalanche Current	Avalanche Current		15	Α
E _{AR}	Repetitive Avalanche Energy		(Note 1)	5.95	mJ
dv/dt	MOSFET dv/dt			100	V/ns
uv/ut	Peak Diode Recovery dv/dt		(Note 3)	20	V/IIS
D	Pawer Dissipation	(T _C = 25°C)		595	W
P_{D}	Power Dissipation - Derate Above 25°C			4.76	W/°C
T _J , T _{STG}	Operating and Storage Temperat	ure Range		-55 to +150	°C
T _L	Maximum Lead Temperature for 1/8" from Case for 5 Seconds	Soldering,		300	°C

Thermal Characteristics

Symbol	Parameter	FCH023N65S3_F155	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.21	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	40	C/VV

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FCH023N65S3_F155	FCH023N65S3	TO-247 G03	Tube	N/A	N/A	30 units

Test Conditions

Min.

Тур.

Max.

Unit

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted. Parameter

Off Chara	acteristics					
DV	Drain to Course Breekdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 25^{\circ}\text{C}$	650	-	-	W
BV _{DSS} Drain to Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 150^{\circ}\text{C}$	700	-	-	V	
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 1 mA, Referenced to 25°C	-	0.72	-	V/°C
1	Zoro Coto Voltago Drain Current	V _{DS} = 650 V, V _{GS} = 0 V	-	-	1	
DSS	Zero Gate Voltage Drain Current	$V_{DS} = 520 \text{ V}, T_{C} = 125^{\circ}\text{C}$	-	6.8	-	μΑ
I _{GSS}	Gate to Body Leakage Current	V _{GS} = ±30 V, V _{DS} = 0 V	-	-	±100	nA

On Characteristics

Symbol

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 7.5 \text{ mA}$	2.5	-	4.5	V
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 37.5 \text{ A}$	-	19.5	23	mΩ
9 _{FS}	Forward Transconductance	V_{DS} = 20 V, I_{D} = 37.5 A	-	66	1	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V _{DS} = 400 V, V _{GS} = 0 V,	-	7160	-	pF
C _{oss}	Output Capacitance	f = 1 MHz	-	195	-	pF
C _{oss(eff.)}	Effective Output Capacitance	V _{DS} = 0 V to 400 V, V _{GS} = 0 V	-	1980	-	pF
C _{oss(er.)}	Energy Related Output Capacitance	$V_{DS} = 0 V \text{ to } 400 V, V_{GS} = 0 V$	- \	298	-	
Q _{g(tot)}	Total Gate Charge at 10V	V _{DS} = 400 V, I _D = 37.5 A,	-	222	-	nC
Q_{gs}	Gate to Source Gate Charge	V _{GS} = 10 V	-	54	-	nC
Q_{gd}	Gate to Drain "Miller" Charge	(Note 4)	-	90	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	0.9	-	Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time			-	45	-	ns
t _r	Turn-On Rise Time	$V_{DD} = 400 \text{ V}, I_D = 37.5 \text{ A},$		- /	55	-	ns
t _{d(off)}	Turn-Off Delay Time	V_{GS} = 10 V, R_g = 2 Ω		-/	140	-	ns
t _f	Turn-Off Fall Time		(Note 4)	-	29	-	ns

Drain-Source Diode Characteristics

Is	Maximum Continuous Drain to Source Dioc	Maximum Continuous Drain to Source Diode Forward Current			75	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current			-	300	Α
V_{SD}	Drain to Source Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 37.5 A	-	-	1.2	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _{SD} = 37.5 A,	-	600	-	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$	-	17.9	-	μС

- 1. Repetitive rating: pulse width limited by maximum junction temperature.
- 2. I_{AS} = 15 A, R_{G} = 25 Ω , starting T_{J} = 25°C.
- 3. I_{SD} \leq 75 A, di/dt \leq 200 A/µs, V_{DD} \leq BV_DSS, starting T_J = 25°C.
- 4. Essentially independent of operating temperature typical characteristics.

Typical Performance Characteristics

Figure 1. On-Region Characteristics

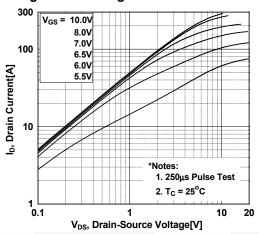


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

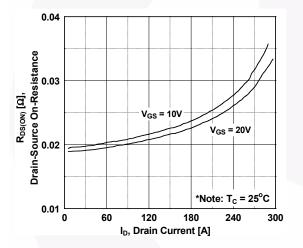


Figure 5. Capacitance Characteristics

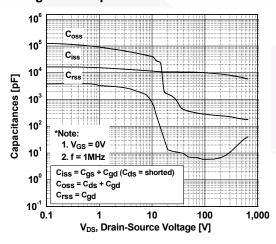


Figure 2. Transfer Characteristics

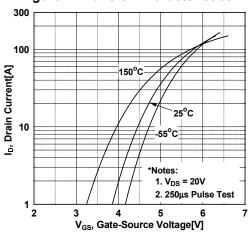


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

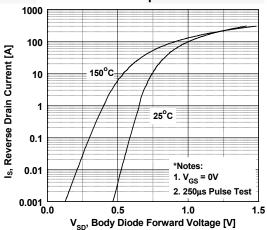
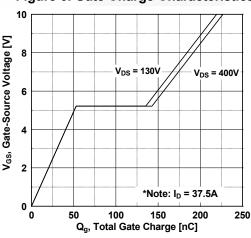


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

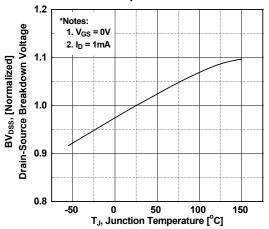


Figure 8. On-Resistance Variation vs. Temperature

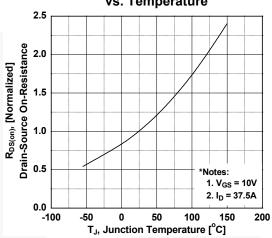


Figure 9. Maximum Safe Operating Area

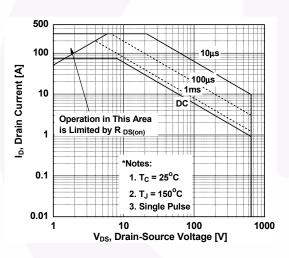


Figure 10. Maximum Drain Current vs. Case Temperature

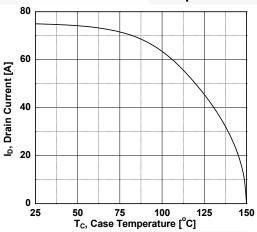
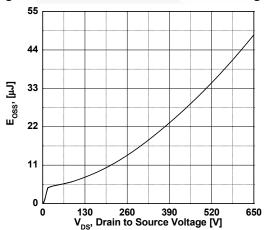
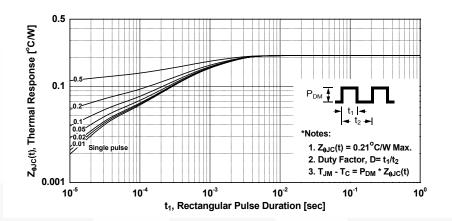


Figure 11. Eoss vs. Drain to Source Voltage



Typical Performance Characteristics (Continued)

Figure 12. Transient Thermal Response Curve



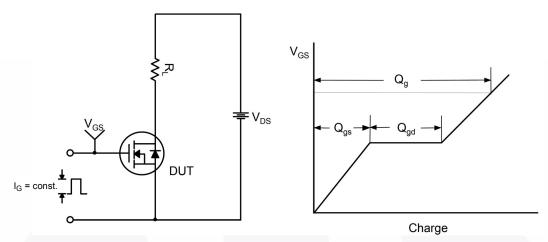


Figure 13. Gate Charge Test Circuit & Waveform

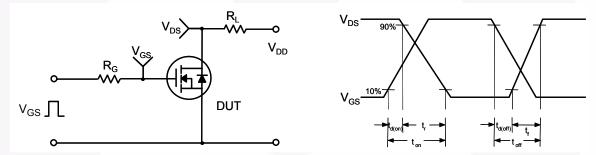


Figure 14. Resistive Switching Test Circuit & Waveforms

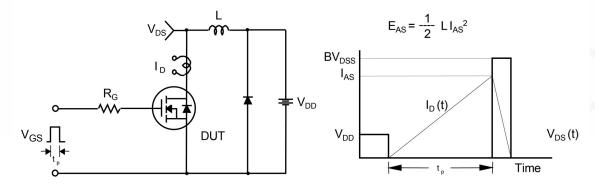


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

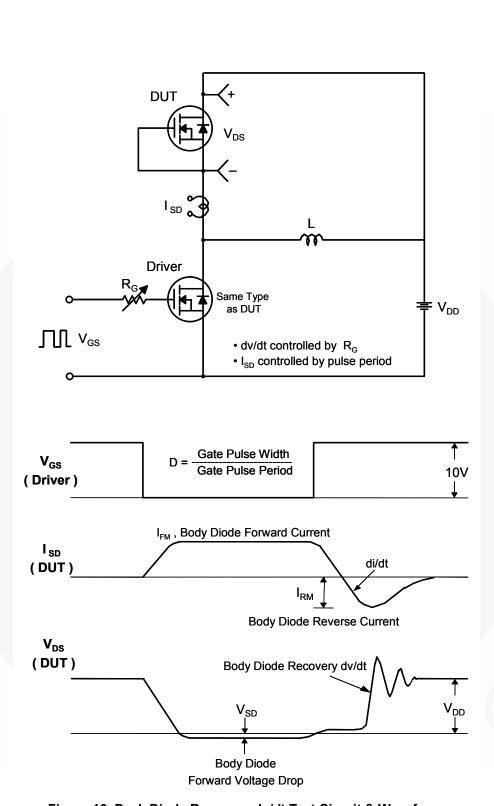
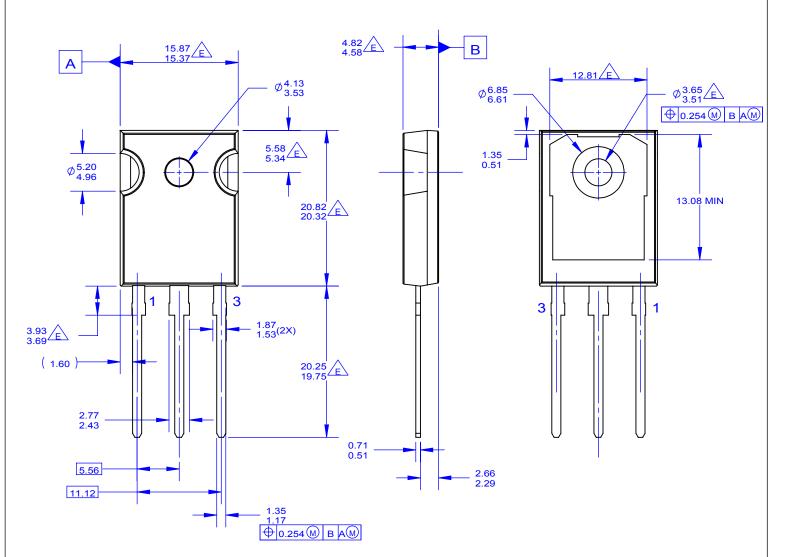


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms



NOTES: UNLESS OTHERWISE SPECIFIED.

- A. PACKAGE REFERENCE: JEDEC TO-247, ISSUE E, VARIATION AB, DATED JUNE, 2004.
- B. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- C. ALL DIMENSIONS ARE IN MILLIMETERS.
- D. DRAWING CONFORMS TO ASME Y14.5 1994





ON Semiconductor and in are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdt/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and exp

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800-282-9855 Toll Free USA/Canada
Europe, Middle East and Africa Technical Support:
Phone: 421 33 790 2910
Japan Customer Focus Center
Phone: 81-3-5817-1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative